

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
Tan Dean D. Nguyen		3689		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,069,234	06-2006	Cornelius et al.	705/26
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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